ANSWER 1 OF 1 SCISEARCH COPYRIGHT 1998 ISI (R) L6

90:76161 SCISEARCH ACCESSION NUMBER:

THE GENUINE ARTICLE: CL594

FORCE MICROSCOPE WITH CAPACITIVE DISPLACEMENT TITLE:

DETECTION

GODDENHENRICH T (Reprint); LEMKE H; AUTHOR:

HARTMANN U; HEIDEN C

KFA JULICH GMBH, INST THIN FILM & ION TECH, POB CORPORATE SOURCE:

1913, W-5170 JULICH 1, GERMANY (Reprint)

**GERMANY** COUNTRY OF AUTHOR:

JOURNAL OF VACUUM SCIENCE & TECHNOLOGY A-VACUUM SOURCE:

SURFACES AND FILMS, (1990) Vol. 8, No. 1, pp.

383-387.

DOCUMENT TYPE: Article; Journal

PHYS; ENGI FILE SEGMENT: LANGUAGE: ENGLISH

REFERENCE COUNT: 14

PHYSICS, APPLIED CATEGORY:

90-0502 004; SCANNING TUNNELING MICROSCOPY; RESEARCH FRONT:

ANOMALOUS FORCE DEPENDENCE; ATOMIC POSITIONS

REFERENCE(S):

Referenced Author (RAU)	(RPY)   (RV)	L) [ (RPG)	·
ABRAHAM D W ANDERS M BINNIG G GODDENHENRICH T GRUTTER P HARTMANN U HARTMANN U HARTMANN U MARTI O MARTIN Y MCCLELLAND G M RUGAR D	1988   53	1446   930   527   279   281   2285   475   2089   1455   4723   1307   2337	APPL PHYS LETT  IN PRESS J MICROSC  PHYS REV LETT
WHITE G K	1961  1	151	CRYOGENICS

L3 ANSWER 1 OF 5 SCISEARCH COPYRIGHT 1998 ISI (R)

ACCESSION NUMBER: 91:130391 SCISEARCH

THE GENUINE ARTICLE: EZ923

TITLE: A NEW FORCE SENSOR INCORPORATING FORCE-FEEDBACK

CONTROL FOR INTERFACIAL FORCE MICROSCOPY

AUTHOR: JOYCE S A (Reprint); HOUSTON J E

CORPORATE SOURCE: SANDIA NATL LABS, ALBUQUERQUE, NM, 87185 (Reprint)

COUNTRY OF AUTHOR: USA

SOURCE: REVIEW OF SCIENTIFIC INSTRUMENTS, (1991)

Vol. 62, No. 3, pp. 710-715.

DOCUMENT TYPE: Article; Journal

FILE SEGMENT: PHYS; ENGI LANGUAGE: ENGLISH

REFERENCE COUNT: 26

ABSTRACT:

A new interfacial-force microscope capable of measuring the forces between two surfaces over the entire range of surface separations, up to contact, is described. The design is centered around a differential-capacitance displacement sensor where the common capacitor plate is supported by torsion bars. A force-feedback control system is incorporated which balances the interfacial forces at the sensor, maintaining the common capacitor plate at its rest position. This control therefore eliminates the instability or "jumping" which occurs with conventional cantilever-based force sensors when the attractive force gradient between the fixed sample and sensor exceeds the mechanical stiffness of the cantilever. The operating characteristics of the sensor and its ability to measure interfacial forces using the feedback control at surface separations smaller than this instability point are demonstrated.

CATEGORY: PHYSICS, APPLIED; INSTRUMENTS & INSTRUMENTATION SUPPL. TERM PLUS: ATOMIC-SCALE FRICTION; TUNGSTEN TIP; SURFACE

RESEARCH FRONT: 91-0497 003; ATOMIC FORCE MICROSCOPY; ELASTIC TIP

SURFACE INTERACTIONS; IMAGING NANOMETER SCALE

DEFECTS IN LANGMUIR-BLODGETT-FILMS

91-4102 001; SURFACE FORCES; ADSORBED LAYERS;

ELECTROSTATIC INTERACTION; AQUEOUS ETHYL(HYDROXYETHYL)CELLULOSE SOLUTIONS

## REFERENCE(S):

Referenced Author (RAU)	Year   VOL   PG  (RPY) (RVL) (RP	G)   (RWK)
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MEYER E	1989  181  527	THIN SOLID FILMS

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